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AU4667001, 🗔 <u>WO0175196</u>	EC Classification:	C30B31/22, C30B33/00, H01L21/762D8B
	Equivalents:	AU4667001, ☐ WO0175196
		Abottot

implantation distributed about a certain value by bombardment of said atomic species on a zone of the ingot (1) cylindrical surface, and an operation which consists in removing (300), at a separation depth located proximate to the depth of implantation, the layer (2) of material located between the surface and the separation depth, to remove said layer (2) from the rest of the ingot (1)

operation which consists in implanting (100) atomic species beneath the surface of a material in the form of a cylindrical ingot (1), at a depth of

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